

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Chul-soo PARK, et al.

Application No.: Unassigned

Group Art Unit: Unassigned

Filed: July 10, 2003

Examiner:

For: PICKUP INSPECTING APPARATUS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure provisions of 37 CFR § 1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the subject application.

1. Enclosures accompanying this Information Disclosure Statement are:

- 1a. ☒ Form PTO-1449.
- 1b. ☒ Copies of IDS citations.
- 1c. ☐ An English language copy of search report(s) from a counterpart foreign application or a PCT International Search Report.
- 1d. ☐ English language translation (Abstract Only) attached to each non-English language publication.
- 1e. ☒ Explanations of Relevancy of References (ATTACHMENT 1(e), hereto) for providing a concise explanation of each non-English publication.

2. ☒ In accordance with 37 CFR § 1.98, a concise explanation of what is presently understood to be the relevance of each non-English language publication is

(Check appropriate Items 2a, 2b, 2c and/or 2d)

- 2a. ☐ satisfied because all non-English language publications were cited on the enclosed "English-language version of the search report or action which indicates the degree of relevance found by the foreign office". (See MPEP 609, Minimum Requirements for an Information Disclosure Statement, Part A(3): Concise Explanation of Relevance, pp. 600-100 to 600-101, Rev. 1, Feb. 2000.)
- 2b. ☐ set forth in the application.

- 2c. ☐ satisfied because an English language translation (Abstract Only) is attached to each non-English language publication.
- 2d. ☒ enclosed as Attachment 1(e), hereto.
3. No admission is made that the information cited in this Statement is, or is considered to be, material to patentability nor a representation that a search has been made (other than search report(s) from a counterpart foreign application or a PCT International Search Report, if submitted herewith). 37 CFR §§ 1.97(g) and (h).

Respectfully submitted,

STAAS & HALSEY LLP

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By: 

Michael D. Stein
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ATTACHMENT 1(e)

EXPLANATIONS OF RELEVANCY OF REFERENCES	ATTORNEY DOCKET NO. 1572.1143	APPLICATION NO. Unassigned
	FIRST NAMED INVENTOR Chul-soo PARK, et al.	
	FILING DATE July 10, 2003	GROUP ART UNIT Unassigned

Patent No.: JP10-124675

Date: May 15, 1998

Title:METHOD FOR INSPECTING CD PRINT SURFACE

Abstract: Relates to an method for inspecting CD print surface

Patent No.: KR 20-0229924

Date: April 27, 20-01

Title:INSPECTION SYSTEM FOR LASER BEAM PICKUP SYSTEM

Abstract: Relates to an inspection system for laser beam pickup system

Patent No.: KR 2002-0006912

Date: January 26, 2002

Title:PICKUP INSPECTION SYSTEM

Abstract: Relates to an pickup inspection system

Patent No.: KR 2002-0060514

Date: July 18, 2002

Title:PICKUP UNIT INSPECTION SYSTEM

Abstract: Relates to an pickup unit inspection system

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>	ATTORNEY DOCKET NO.	APPLICATION NO.
	1572.1143	Unassigned
	FIRST NAMED INVENTOR	
	Chul-soo PARK, et al.	
	FILING DATE	GROUP ART UNIT
	July 10, 2003	Unassigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO
	AG	JP10-124675	5/15/1998	Japan				
	AH	KR 20-0229924	4/17/2001	Korea				
	AI	KR 2002-0006912	1/26/2002	Korea				
	AJ	KR 2002-0060514	7/18/2002	Korea				
	AK							
	AL							

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

	AM	
	AN	
	AO	

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	